

Wintest Corp. CORPORATE PROFILE





Always leading the way in advanced device testing

https://www.wintest.co.jp/

Company Profile

Company Name	Wintest Corp.
President	JIANG HUI
Listing	TSE Standard 6721
HQ Address	1-2-24 Hiranuma, Nishi-ku, Yokohama, Kanagawa Prefecture
O s a k a A d d r e s s	3-13-10, Kita Ward, Nagara Naka, Osaka City Osaka Prefecture,
Established	Aug., 1998
Capital	16.27 Oku Yen (As of Dec.31, 2024)
Number of Employees	96 employee
Affiliated companies	Wuhan Jingce Electronic Group Co.,Ltd. (Wintest Wuhan)
Business Contents	Development, manufacturing, sales and support of automatic semiconductor inspection equipment (ATE)

Mission · Vision · Value

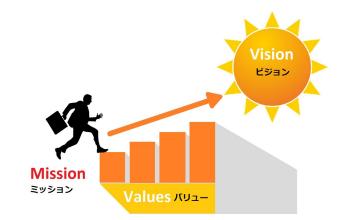
Mission (Our mission, reason for existence) We contribute to the enrichment and happiness of people and the development of society through automated semiconductor inspection technology.

Vision (What we want to be in the future)

We aim to be a top leader in displays and peripheral devices, the main interface that connects people and digital, and grow into a global company.

Value (What we value)

- 1. Customer satisfaction comes first.
- 2. 2. We always create and challenge ourselves in our own business field, aiming to be No. 1.
- 3. We contribute to customers through high product quality and continuous improvement.
 We quickly turn the PDCA cycle and achieve our goals with a sense of urgency.
 We build a rich and fulfilling life through our work.



Initiatives toward SDGs through ESG



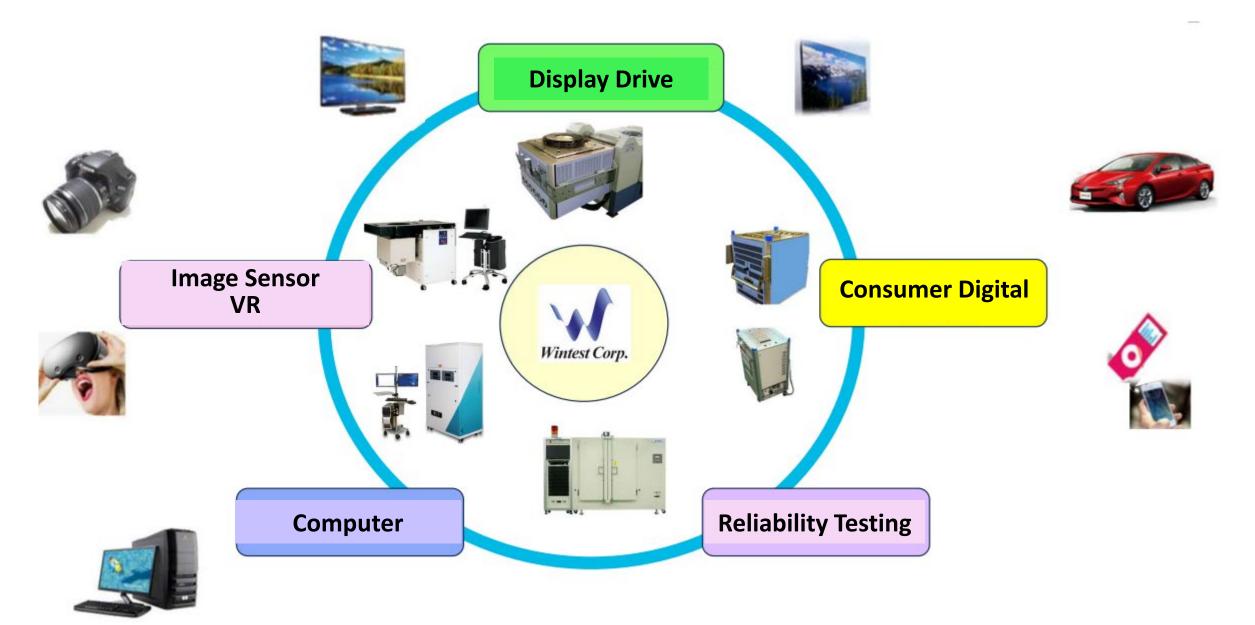
We are aware of the importance of proactively and proactively contributing to the sustainability issues of our country and the entire global society and economy by reviewing the structure and configuration of each piece of energy-consuming equipment, achieving the lowest power consumption in the industry, and working to reduce redundant functions, and we are using our management and development resources to contribute to the realization of a low-carbon society.

Wintest Co., Ltd.'s main business

Our company is a manufacturer of inspection equipment for cutting-edge semiconductor devices.

We develop, design, sell and provide technical support for automatic inspection equipment used in the semiconductor manufacturing process, primarily for the inspection of driving ICs for flat panel displays and image sensors.

There are many final products around us, such as smartphones, televisions, and PCs, that incorporate semiconductors inspected by our equipment.



History

August 1993: Wintest Co., Ltd. Established

July 1995: Sales of the first inspection tester, LCD/CCD/CIS Tester WTS-103C, begin

September 2003: Listed on the Tokyo Stock Exchange Mothers Market

September 2003: Sales of LCD/OLED/CCD/CIS Tester WTS-311 begin

December 2009: Sales of Display Driver IC Tester WTS-577 begin

March 2019: Osaka office established

December 2019: Subsidiary Wintest Wuhan established

April 2022: Change to the Tokyo Stock Exchange Standard Market

The role of our semiconductor inspection equipment

Our inspection equipment supplies power and signals to operate the IC chip (semiconductor) being inspected, and compares the signals output from the IC chip with reference data (sample) to identify defective chips. There are many different types of semiconductors, and we have the optimal inspection equipment for each type.

Our semiconductor inspection equipment manufacturing line



History of inspection equipment development



Introducing our new products

LCD/PDP/OLED driver IC Test System

WTS-577SX



Max. operating frequency is 3.2Gbps Max. data transfer speed is 17Gbps. High-speed processing of large amounts of inspection data I/O speed is 1.6GbpsAir-cooled, the fastest model in the industry



Maximum operating frequency is 4.5Gbps Wintest's flagship model I/O speed 1.6Gbps Water cooling method

WTS-9000

Semiconductor Test System lineup

LCD/PDP/OLED driver IC Inspection equipment for R&D	OLED/LCD/LCOS array/large CMOS image sensor inspection equipment		
WTS-588D Compact High-end R&D LCD/PDP/OLED DDIC test system	WTS-311NXSimultaneous measurement of up to 4 large and 32 small Maximum 380 million pixels captured at once Data transfer speed 17GbpsSingle-lens reflex camera (large sensor) Supports low-noise sensor inspection for space use		
Logic IC Test equipment	Analog/Mixed Signal IC Test Equipment		
WTS-3000/ WTS-677	WTS-750/800		



Tester-in-test head configuration. High speed, space-saving, energy-saving Compatible with linear device IC inspection Specialized for generalpurpose logic IC inspection



Power supply device/IPM High voltage (2000V), high current (300A)Supports mixed analog/digital Ics Supports asynchronous (ASync) function Simultaneous measurement of different types

小型CMOSイメージセンサー検査装置

品質保証部門用バーンイン



WTS-377

Supports simultaneous measurement of up to 64 items Up to 280 million pixels captured at once Data transfer speed 17Gbps Digital cameras, mobile phones, CMOS image sensors for automotive use



Monitor burn-in BI-M series Dynamic burn-in BI-D Test burn-in BI-T series QAT (quality assurance) monitor burn-in

Compatible with various logic, analog, memory, and ASIC (-55 degrees)

Domestic and overseas bases

Location	R&D	Manufacturing	Tech Support	Applied Technology	Sales
Yokohama HQ					
Osaka Office					
Wuhan Jingce Electronic Group					
Suzhou office					
Taiwan office					



%*Scheduled to be
established soon



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